Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/661,548	KLINK, JOACHIM	
Examiner	Art Unit	

Steven H.D Nguyen

2616

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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IEEE MPLS	Ц	8/		
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